



**Characteristics of The New Pd-based Alloy for Probe-pins, TK-FS,  
which has three unique features: High Hardness/High Electrical  
Conductivity/High Ductility**



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# Outline

- **ABOUT TANAKA PRECIOUS METALS**
- **Probe-pins types required in semiconductor manufacturing process**
- **Characteristics of materials required for each types of Probe-pins**
- **Characteristics of The New Pd-based Alloy for Probe-pins, TK-FS**
- **Manufacturing process of TK-FS**

# ABOUT TANAKA PRECIOUS METALS

## Group Network

### TANAKA HOLDINGS Co., Ltd.

Strategic and efficient group management and management group companies as the holding company at the center of the TANAKA PRECIOUS METALS.

### TANAKA KIKINZOKU KOGYO K.K.

Sales of precious metals (platinum, gold, silver, and others).  
Manufacture, sales, import and export of various types of industrial precious metals products. Refining and recycling of precious metals.

### TANAKA DENSHI KOGYO K.K.

Manufacturing of various holding wires, and provision of technical services globally.

### EEJA Ltd.

Development, manufacture, sales and export of precious metal and base metal plating solutions, additives and surface treatment-related chemicals.

### Metalor Technologies International SA

Precious metals recovery and refining, production and sales of electrical contacts, and production and sales of plating solutions and plating equipment.

### TANAKA KIKINZOKU JEWELRY K.K.

Retailing of gold and platinum jewelry, diamond jewelry, bridal jewelry and precious metals art objects, selling and buying of gold and platinum bullion bars and coins, remodeling and recycling used jewelry (RE:TANAKA).

# ABOUT TANAKA PRECIOUS METALS

**1885**

Started Money Exchange business as "Tanaka Shoten" in Tokyo

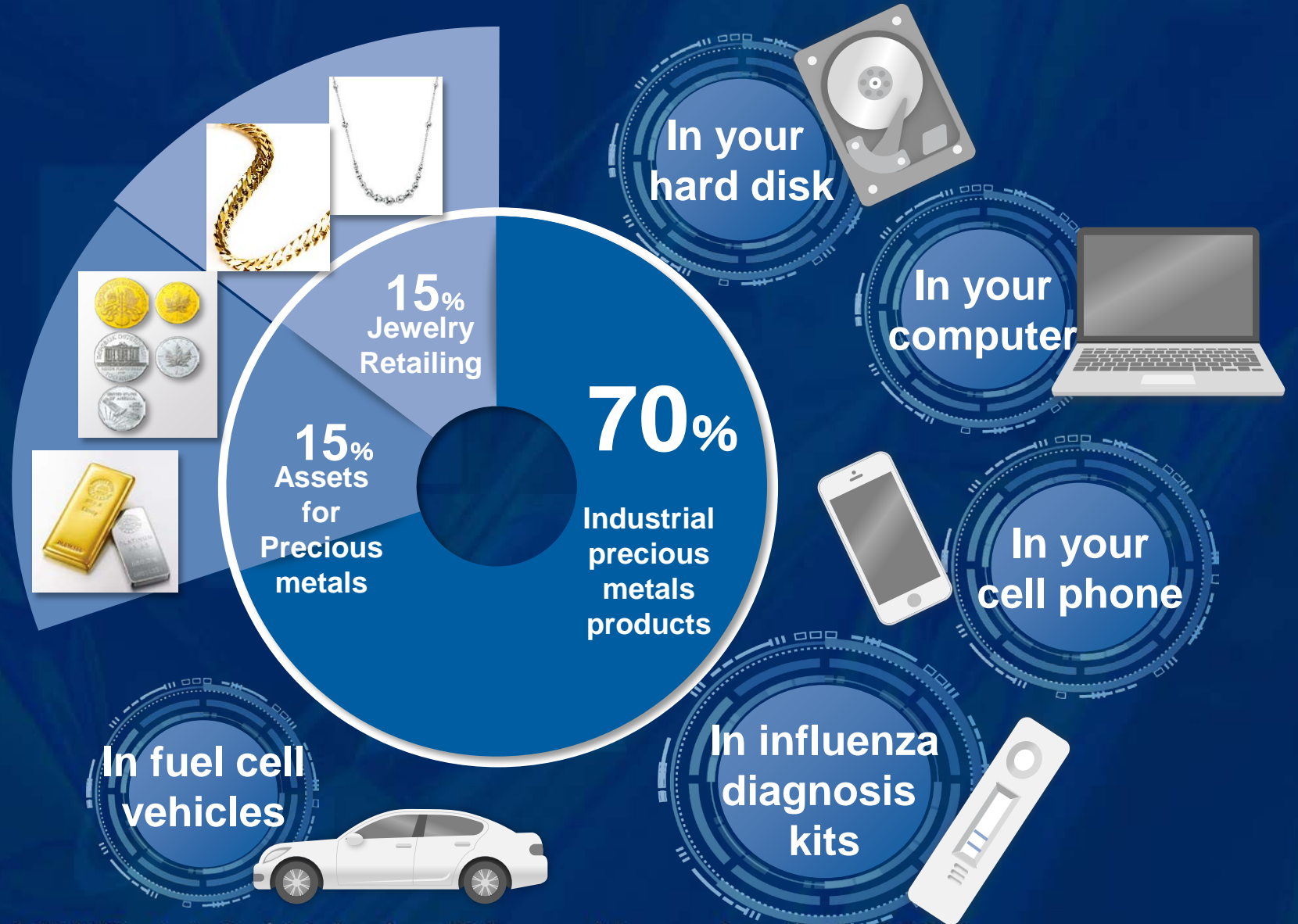
**2022**

**680 Billion JPY**

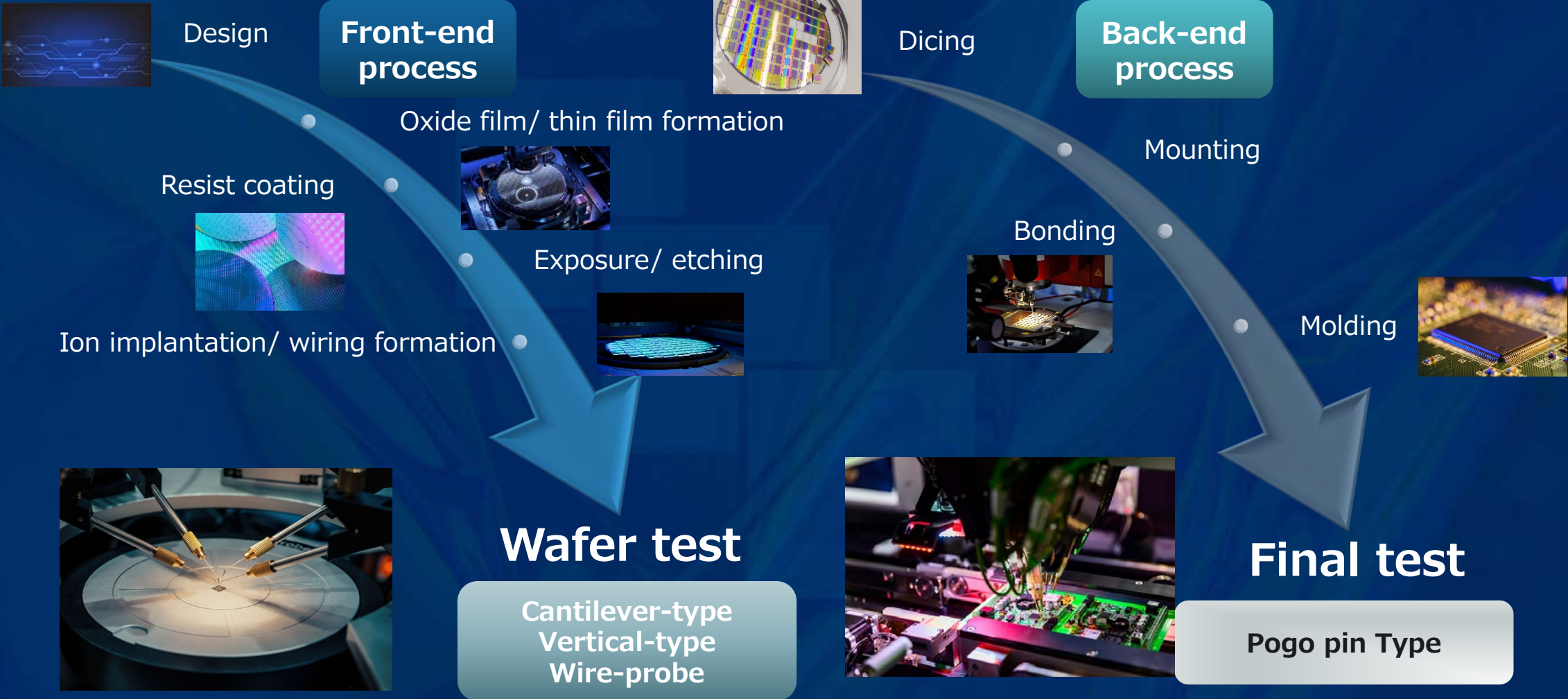
Net sales (consolidated)

**5,355**

Employees (consolidated)



# Probe-pins types required in semiconductor manufacturing process



# Characteristics of materials required for each types of Probe-pins

**Cantilever**  
(Wafer test)

High  
Electrical  
Conductivity

High  
Ductility

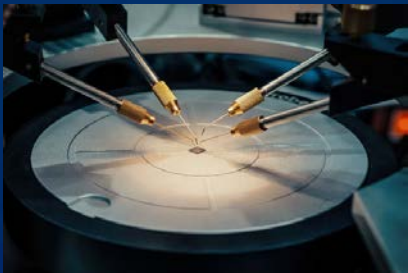
**Vertical**  
(Wafer test)

High  
Hardness  
(Long life)

High  
Electrical  
Conductivity

**Pogo pin**  
(Final test)

High  
Hardness  
(Long life)



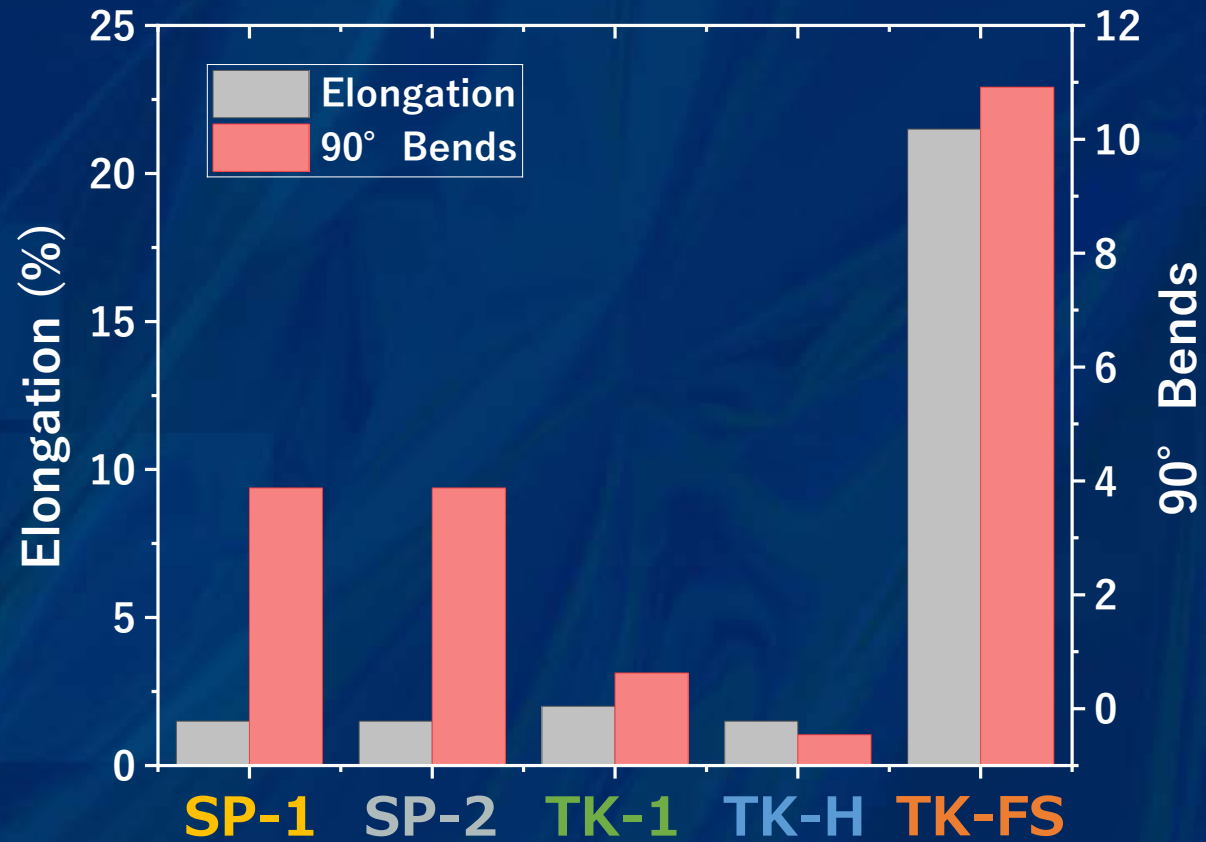
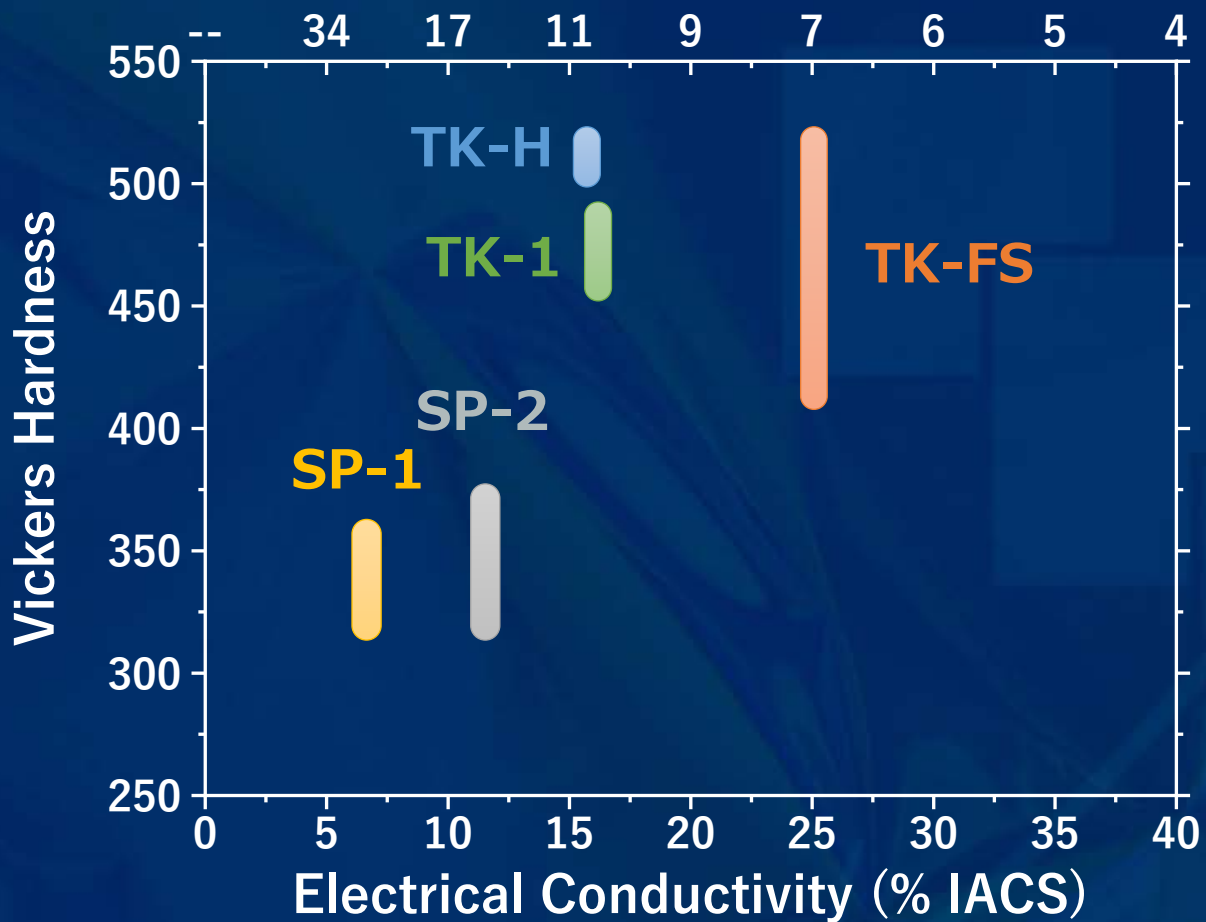
# Major Materials for Probe-pins at TANAKA PRECIOUS METALS

	SP-1 (Pd-Ag-Cu-Pt-Au)	SP-2 (Au-Ag-Cu-Pt)	TK-1 (Pd-Ag-Cu)	TK-H (Pd-Ag-Cu)	TK-FS* (Pd-Ag-Cu)	Rh*	Ir*
<b>Hardness (HV)</b>	300-350	300-360	460-490	500-520	400-520	400-550	500-750
<b>Young's modulus (GPa)</b>	112	106	110	112	150	380	530
<b>Electrical Conductivity (%IACS)</b>	6.9	13.3	16.6	16.3	25-29	35.9	30.8
<b>Elongation at failure (%)</b>	1-2	1-2	1-3	1-2	13-30	1-2	1-2
<b>90° Bends (times)</b>	3-6	3-6	1-2	0-1	8-14	-	-

\*Patent registered

# Comparison of Major Materials for Probe-pins

Electrical Resistivity ( $\mu\Omega \cdot \text{cm}$ )





# Characteristics of The New Pd-based Alloy for Probe-pins, “TK-FS”

## Conductivity

**25-29%IACS**

TK-1: 16.6%IACS

## Hardness

(Adjustable widely)

Max. **520HV**

~ Min. 400HV

TK-1: 460-490HV

## Ductility

EL: **13-30%**

90°Bends: **8-14**

TK-1:

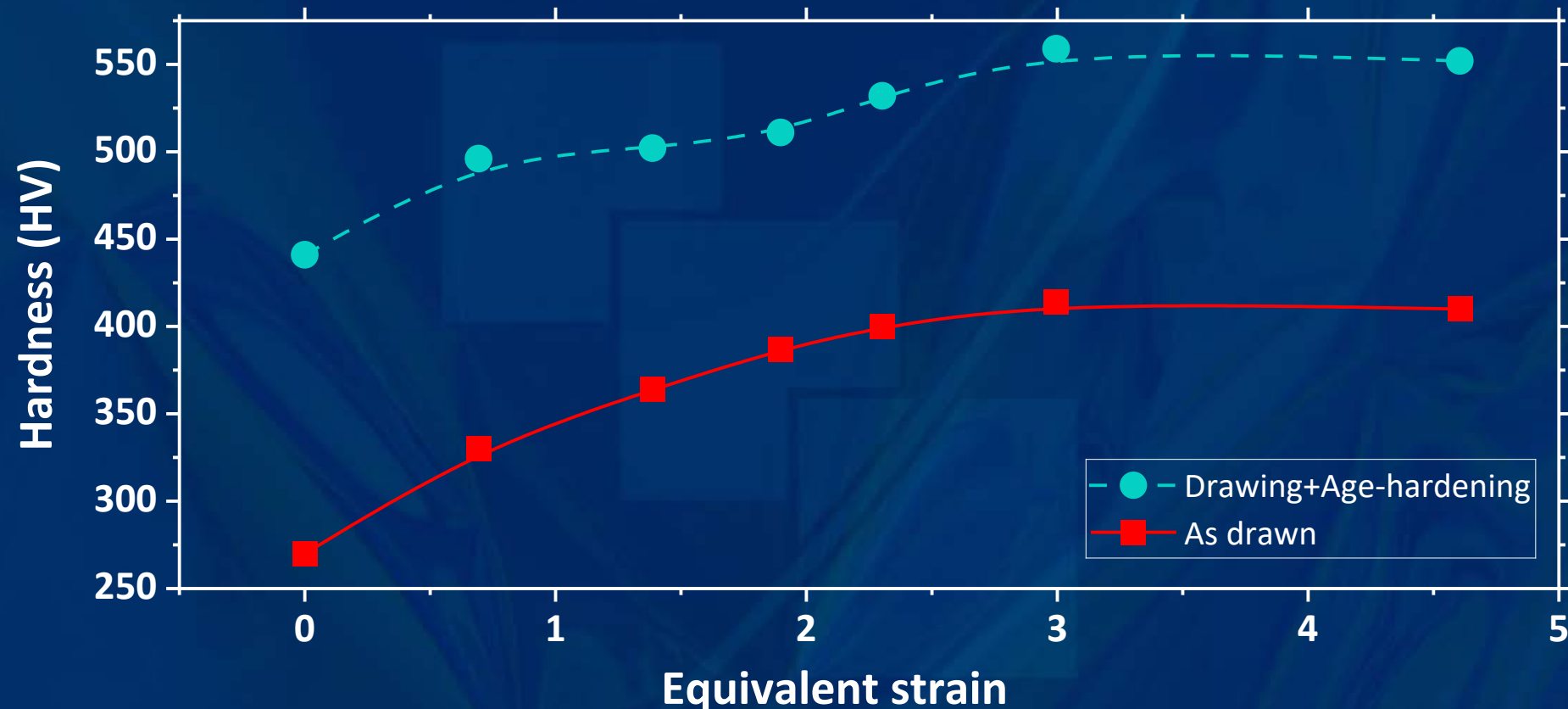
EL: 1-3%

90°Bends: 1-2

**TK-FS can be applied to various types of Probe-pins**

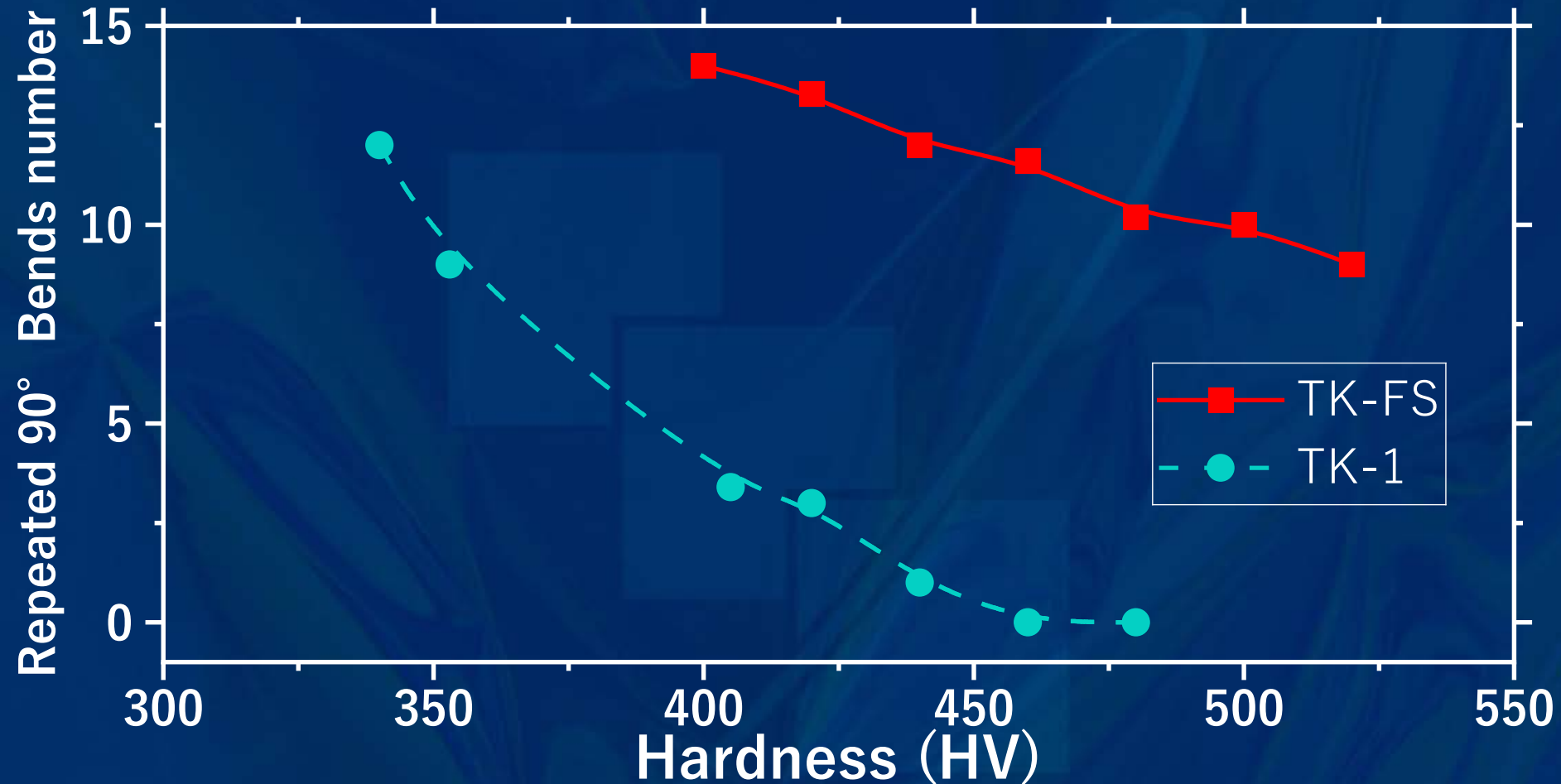
# Work hardening behavior of “TK-FS”

Equivalent strain dependence of Hardness of TK-FS



**TK-FS becomes harder with increasing Equivalent strain, saturating in hardness at 3 or higher.**

# Hardness vs 90° Bends (comparison of “TK-FS” and TK-1)

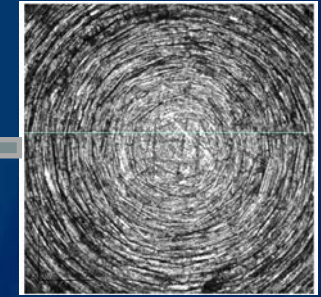
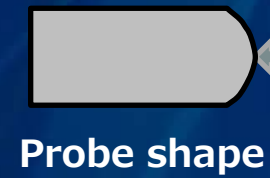
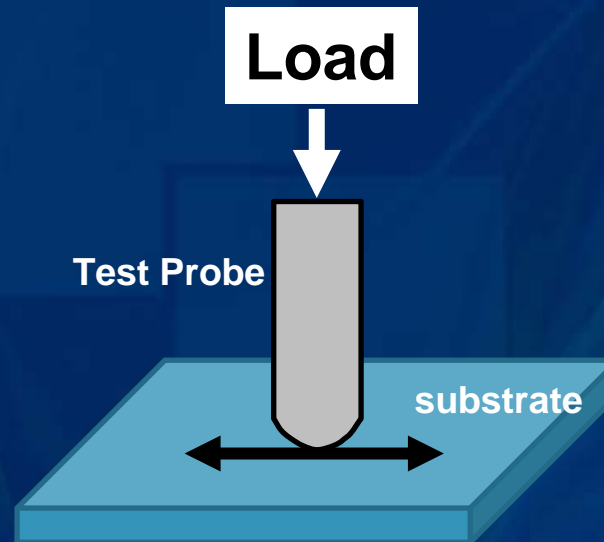


The conventional material (TK-1) could not withstand bending with exceeding 450HV. However, TK-FS exhibits **excellent bending durability even over 500HV**.

# Wear test

## Test Condition

Probe Material: TK-FS/TK-H/TK-1  
Probe Dimension:  $\phi 0.93\text{mm} \times 16\text{mmL}$   
Probe Tip Shape: SR0.03-0.05  
Stroke: About 1mm  
Test Speed: 20mm/sec (10Hz)  
Test Load: 20, 40gf  
Test Temperature: R.T.



Surface of Probe Tip  
(before test)

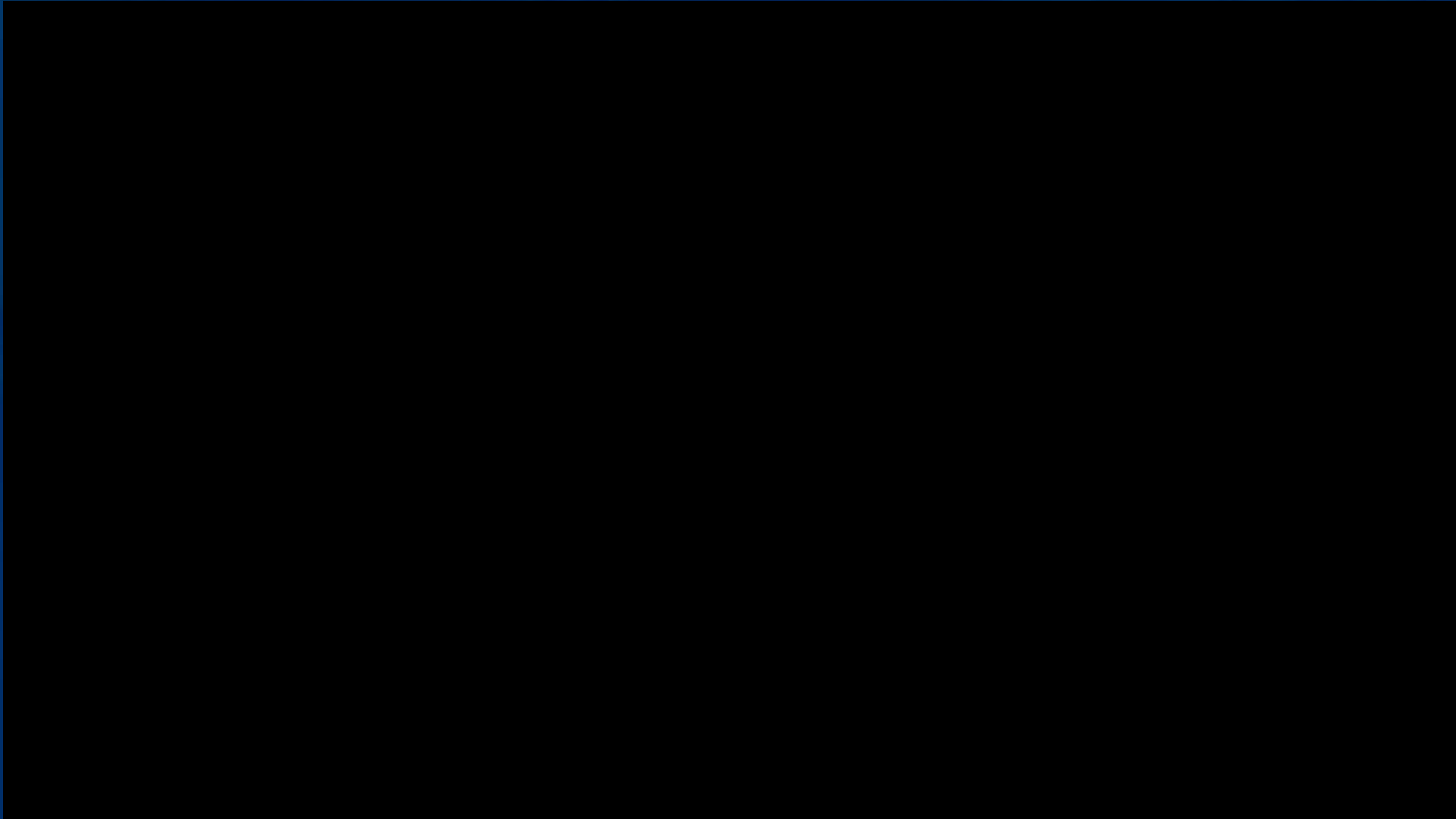


Au Plating (0.10 $\mu\text{m}$ )

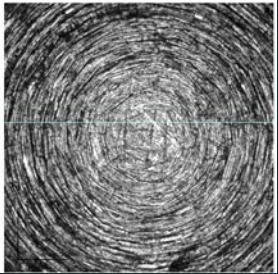

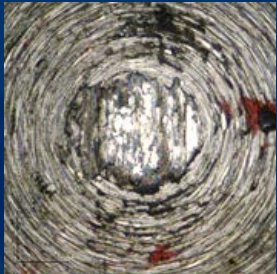

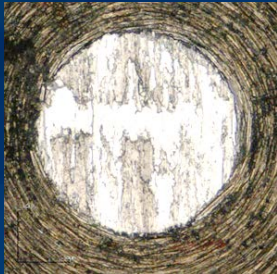



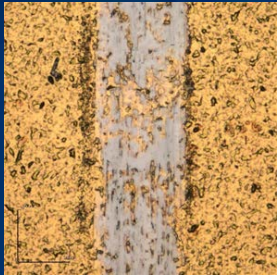
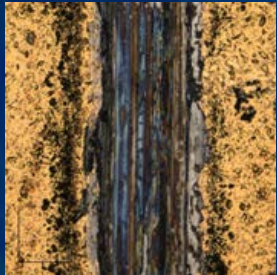


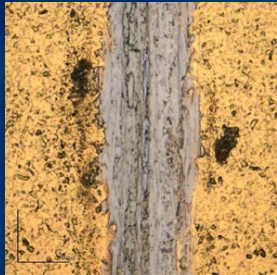
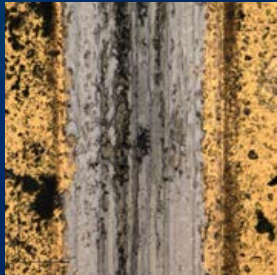
Pd Plating (0.10 $\mu\text{m}$ )

Ni Plating (3~6 $\mu\text{m}$ )

Cu base plate

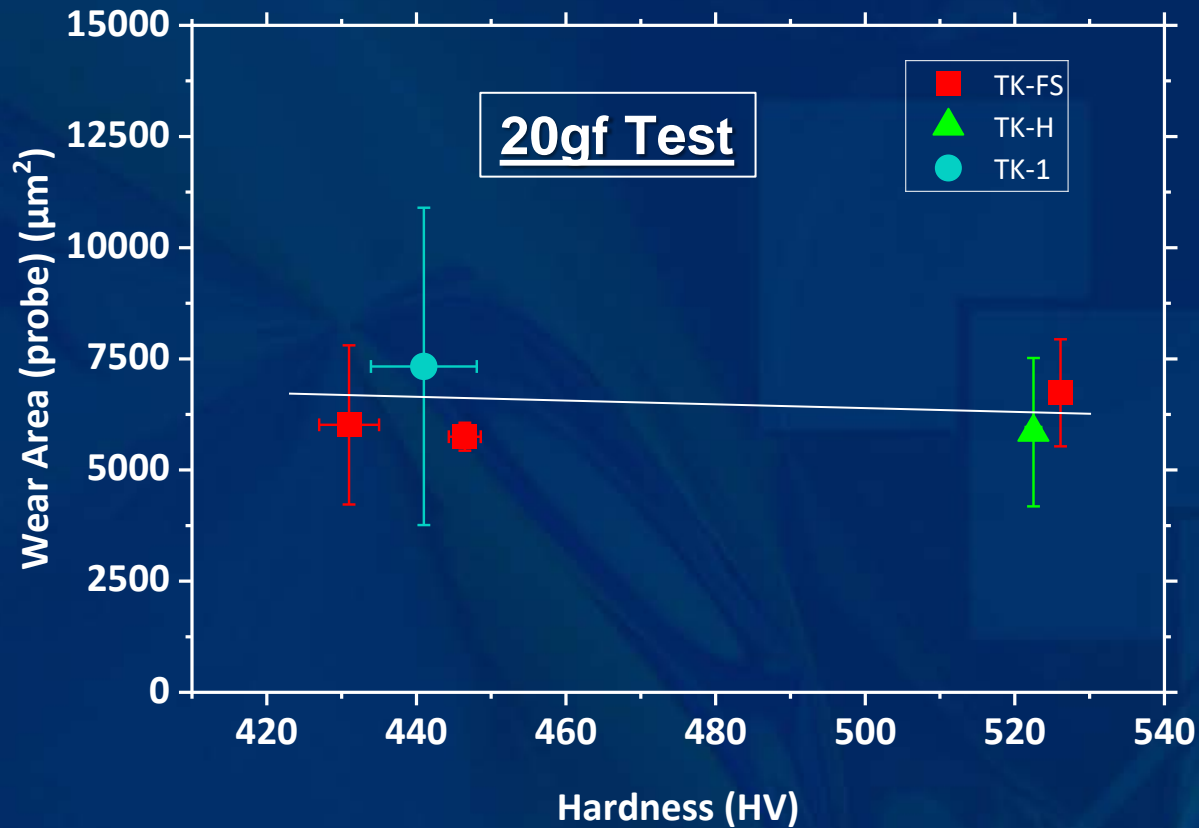


# Surface of Probe tip and substrate (before / after test)

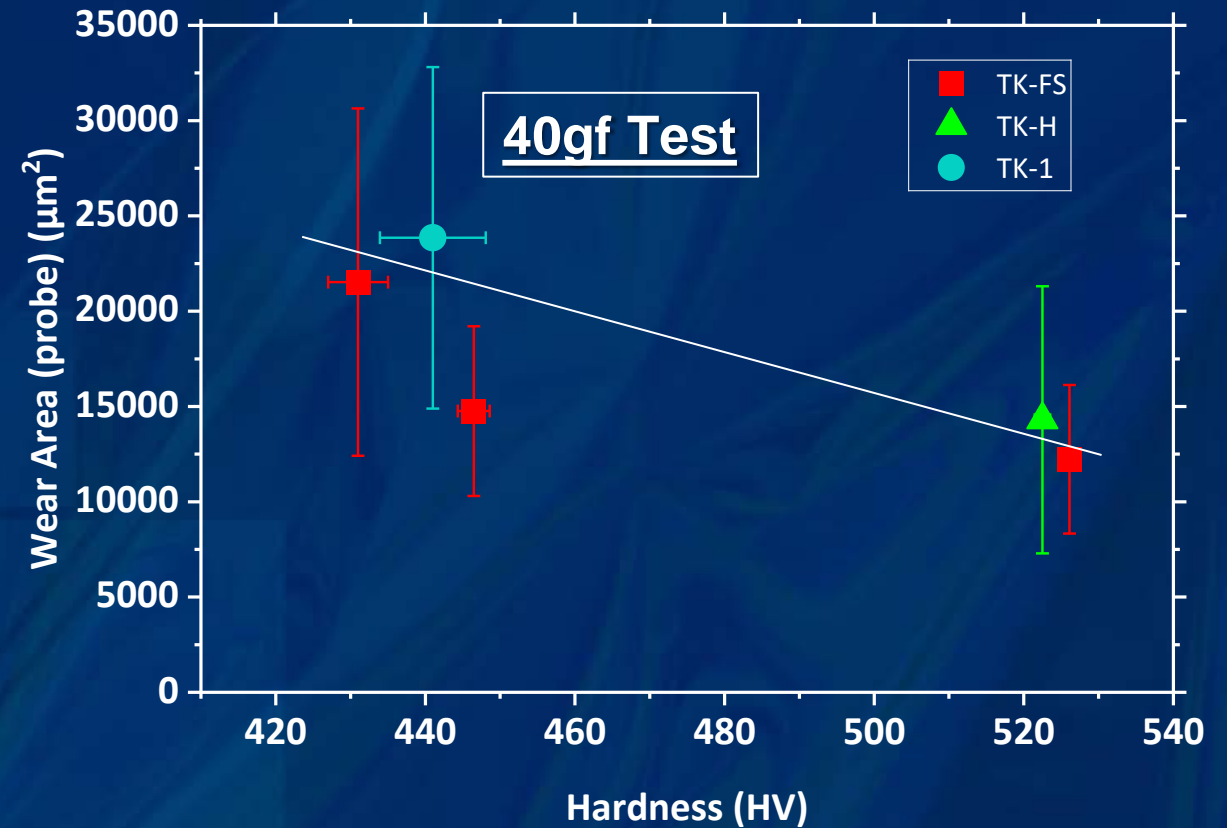
	Before	After					
		TK-FS (520HV)		TK-1 (440HV)		TK-H (520HV)	
		20gf	40gf	20gf	40gf	20gf	40gf
Tip							
Substrate							

# Wearing behavior of Pd-based materials

Wearing area vs Hardness (20gf)

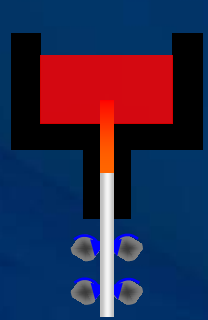


Wearing area vs Hardness (40gf)

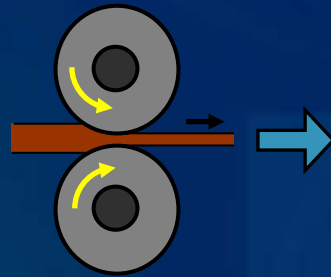


20gf test: Wear area shows almost same, NOT affected by the hardness of materials.  
40gf test: Wearing area decreases with increasing the hardness of materials.

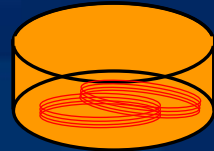
# Manufacturing Process of Pd-based materials



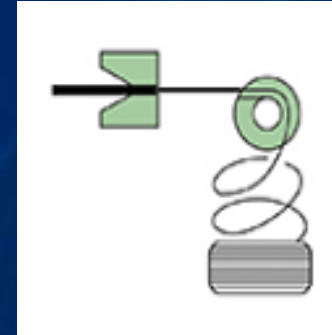
Continuous casting



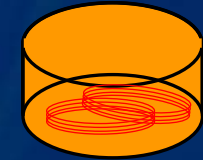
Groove rolling



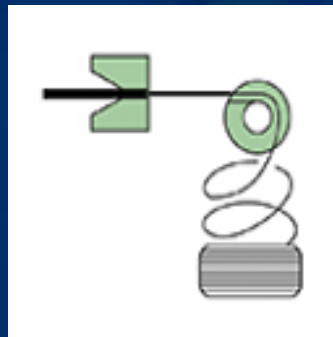
Heat treatment



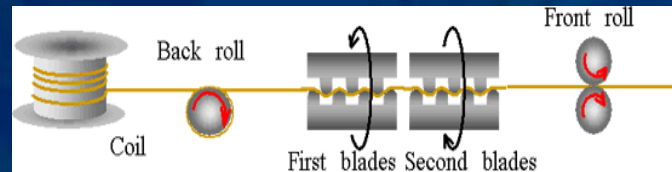
Drawing



Heat treatment



Drawing



Straightening



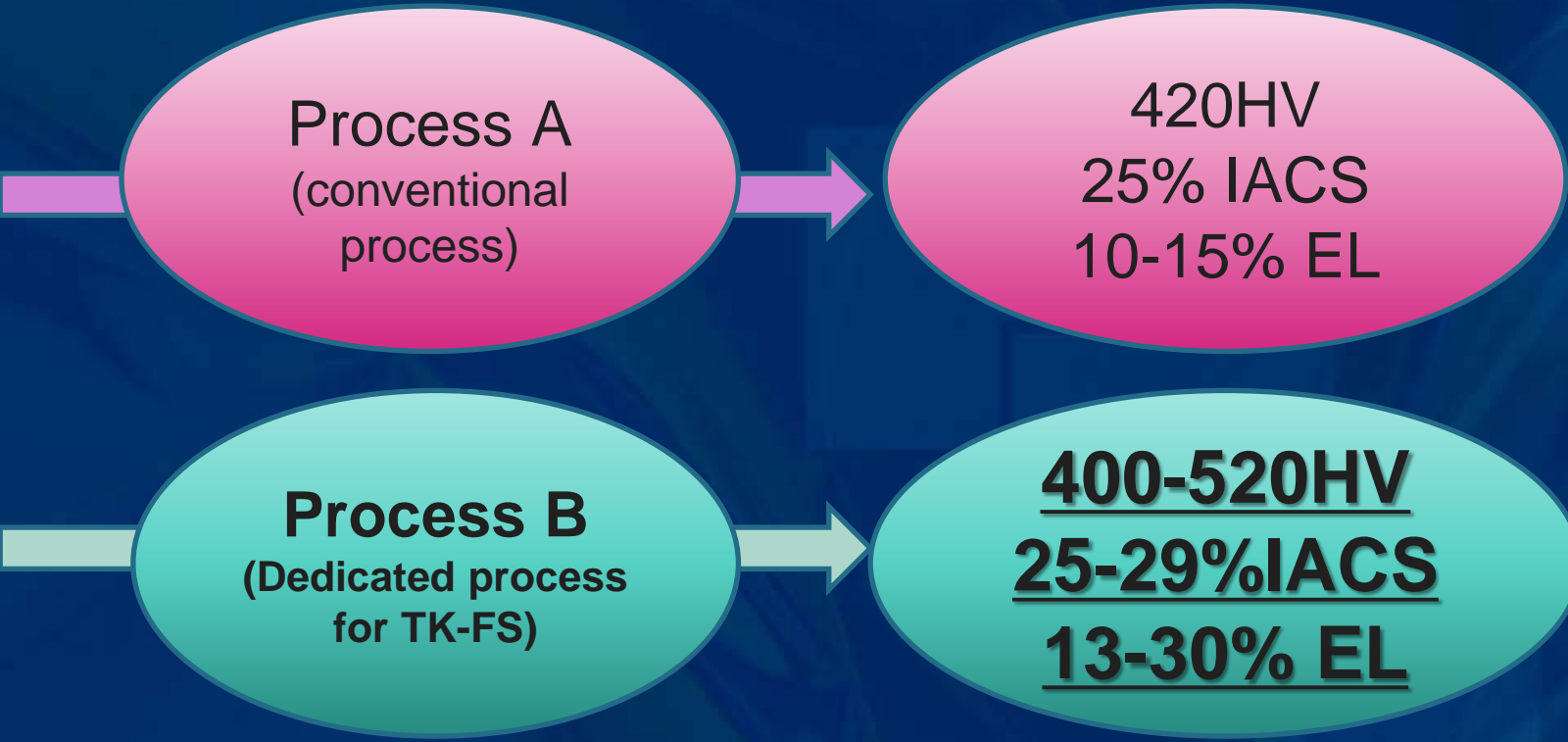
Inspection



Shipping



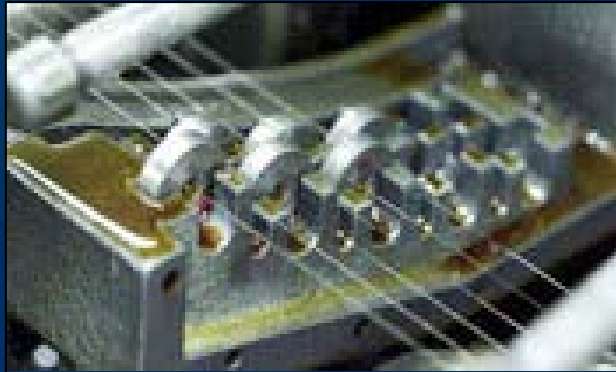
# Manufacturing Process of TK-FS



	Process A	Process B
Hardness (HV)	420	<b>400-520</b>
Young's modulus (GPa)	115	<b>150</b>
Electrical Conductivity (%IACS)	25	<b>25-29</b>
Elongation (%)	10-15	<b>13-30</b>
90° Bends	8-10	<b>8-14</b>

The TK-FS dedicated process (Our know-how) allows a wide range of adjustments in each characteristics, although only a limited range of properties could be achieved with the conventional process.

# Capable wire diameter / Future business of “TK-FS”



We have already succeeded in manufacturing 0.03 to 1.0mm in diameter, and are trying to manufacture less than 0.03mm products.



Foil type products (0.02~0.1mm in thickness) are also been trying to establish manufacturing process.

We plan to replace various current Pd-based Probe-pins materials with TK-FS in the future!

# Conclusion

- Depending on the types of probe-pins using in the semiconductor manufacturing process, high hardness, high electrical conductivity and high ductility are required for Probe-pins materials.
- TK-FS can be applied to various types of Probe-pins. TK-FS is manufactured by the dedicated process and its characteristics are widely adjustable.
- In the wear test, the results are different in the test load. (At high load test, Wearing area decreases with increasing the hardness of materials.)
- We have already succeeded in manufacturing TK-FS fine wire with 0.03 to 1.0mm in diameter, and are trying to manufacture less than 0.03mm in diameter, and also foil products with 0.02~0.1 mm in thickness.
- We plan to replace various current Pd-based Probe-pins materials with TK-FS in the future.



# THANK YOU !

Let's discuss in detail about "TK-FS" at Our Exhibition Booth (#500)!!

Web Site: <https://tanaka-preciousmetals.com/en/products/detail/probe-pins/>

